

MOS INTEGRATED CIRCUIT μ PD78F9210FH, 78F9211FH, 78F9212FH

8-BIT SINGLE-CHIP MICROCONTROLLER

The μ 78F9210FH, 78F9211FH, and 78F9212FH are products of the 78K0S/KY1+ in the 78K/0S series.

These microcontrollers feature Single-voltage and Self-programming Flash memory and peripherals that is suitable for your application.

The functions of these microcontrollers are described in the following user's manuals. Refer to these manuals when designing a system based on any of these microcontrollers.

78K0S/KY1+ User's Manual : U16994E 78K/0S Series User's Manual, Instruction : U11047E

FEATURES

- 78K/0S CPU core, 8-bit CISC architecture
- ROM and RAM capacities

Item	Program memory	Data memory
Product name	(Flash EEPROM)	(High-speed RAM)
μPD78F9210FH	1 Kbytes	128 bytes
μPD78F9211FH	2 Kbytes	128 bytes
μPD78F9212FH	4 Kbytes	128 bytes

• Minimum instruction execution time

Minimum instruction execution time selectable from high speed (0.2 μ s) to low speed (3.2 μ s) (with CPU clock of 10 MHz)

System clock

High-speed internal oscillator: 8 MHz (TYP.) Ceramic/crystal oscillator: 1 MHz to 10 MHz

• WDT clock

Low-speed internal oscillator: 240 kHz (TYP.)

Interrupt

External: 2 sources Internal: 5 sources

• I/O port: 14

CMOS I/O: 13 CMOS Input: 1

On-chip A/D Converter

10-bit resolution A/D converter: 4 ch (2.7 to 5.5 V)

• Timer/Counter

16-bit Timer: 1 ch 8-bit Timer: 1 ch

• Watchdog Timer: 1 ch

Operation Voltage: 2.0 V to 5.5 V

 Package: 16-pin WLCSP (1.93 x 2.24 x thickness of 0.4 mm, 0.5 mm pitch)

APPLICATION FIELDS

Household electrical appliances, Toys, Mobile device

The information contained in this document is being issued in advance of the production cycle for the product. The parameters for the product may change before final production or NEC Electronics Corporation, at its own discretion, may withdraw the product prior to its production. Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.



ORDERING INFORMATION

Part Number	Package
μPD78F9210FH-2A2-A	16-pin WLCSP (1.93x2.24x0.4 mm in thickness, 0.5 mm pitch)
μPD78F9211FH-2A2-A	16-pin WLCSP (1.93x2.24x0.4 mm in thickness, 0.5 mm pitch)
μPD78F9212FH-2A2-A	16-pin WLCSP (1.93x2.24x0.4 mm in thickness, 0.5 mm pitch)

Remark Products with -A at the end of the part number are lead-free products.



OVERVIEW OF FUNCTIONS

Item		μPD78F9210FH	μPD78F9211FH	μPD78F9212FH		
Internal memory	Flash memory	1 KB	2 KB	4 KB		
	High-speed RAM ^{Note 1}					
Memory space		64 KB				
X1 input clock (osci	llation frequency)	Crystal/ceramic oscillation 10 MHz: V _{DD} = 2.0 to 5	n, external system clock in .5 V	put		
Internal oscillation	High-speed	Internal oscillation: 8 MHz	z (TYP.)			
clock	Low-speed	Internal oscillation: 240 kl	Hz (TYP.)			
General-purpose re	gisters	8 bits × 8 registers				
Instruction execution	n time	0.2 μs/0.4 μs/0.8 μs/1.6 μ	μ s/3.2 μ s/ (X1 input clock:	@ fx = 10 MHz operation)		
I/O ports		Total: CMOS I/O: CMOS Input	<u>14</u> 13 1			
Timers	Timers		 16-bit timer/event counter: 1 channel 8-bit timer(Timer H1): 1 channel Watchdog timer: 1 channel 			
	Timer outputs	2 (PWM output: 1)				
A/D converter		10-bit resolution × 4 channels				
Vectored interrupt	External	2				
sources	Internal	5				
Reset		 Reset using RESET pin Internal reset by watchdog timer Internal reset by power-on-clear Internal reset by low-voltage detector 				
Power supply voltage	ge	$V_{DD} = 2.0 \text{ to } 5.5 \text{ V}^{\text{Note}}$				
Operating ambient	temperature	$T_A = -40 \text{ to } +85^{\circ}\text{C}$				
Package		16-pin WLCSP				

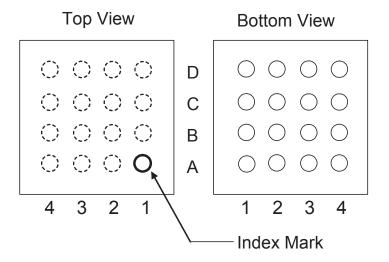
Note Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on-clear(POC) circuit is 2.1 V \pm 0.1 V.

CONTENTS

1.	PIN CONFIGURATION	5
2.	BLOCK DIAGRAM	6
3.	PIN FUNCTIONS	7
	3.1 Port Pins	
	3.2 Non-Port Pins	
	3.3 Pin I/O Circuits and Recommended Connection of Unused Pins	9
4.	MEMORY SPACE	11
	4.1 Memory Space	11
	4.2 Memory Configuration	14
5.	OPTION BYTE	15
	5.1 Functions of Option Byte	15
	5.2 Format of Option Byte	
6.	SOURCE CLOCK OF EACH TIMER	18
7.	ELECTRICAL SPECIFICATIONS (TARGET VALUES)	19
8.	PACKAGE DRAWING (PRELIMINARY)	31
ΔΡ	PENDIX A RELATED DOCUMENTS	32

1. PIN CONFIGURATION

• 16-pin WLCSP (1.93x2.24x0.4 mm in thickness, 0.5 mm pitch)



Pin No.	Pin Name	Pin No.	Pin Name
A1	P20/ANI0/TI000/TOH1	C1	P42
A2	Vss ^{Note1}	C2	P43
A3	P47	C3	P34/RESET
A4	P23/X1/ANI3	C4	P45
B1	P41	D1	P21/ANI1/TI010/TO000/INTP0
B2	P40	D2	P32/INTP1
В3	V _{DD} ^{Note2}	D3	P44
B4	P46	D4	P22/X2/ANI2

ANI0 to ANI3: Analog input TI000, TI010: Timer input INTP0, INTP1: External interrupt input TO00, TOH1: Timer output V_{DD}^{Note2}: P20 to P23: Port 2 Power supply Vss^{Note1}: P32, P34: Port 3 Ground

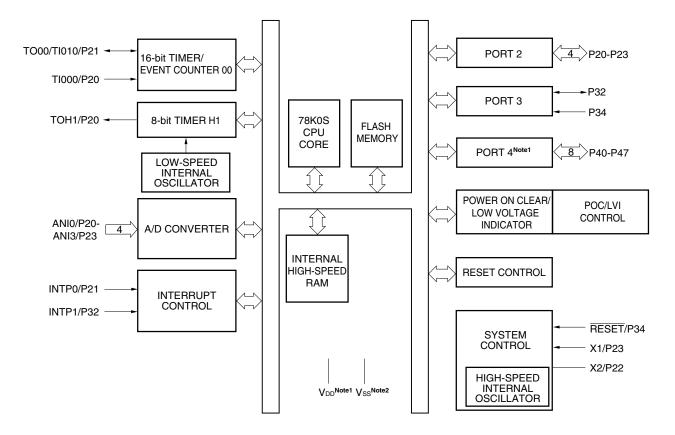
P40 to P47: Port 4 X1, X2: Crystal oscillator (X1 input clock)

RESET: Reset

Notes 1. Vss functions alternately as the ground potential of the A/D converter. Be sure to connect Vss to a stabilized GND (= 0 V).

2. V_{DD} functions alternately as the A/D converter reference voltage input. When using the A/D converter, stabilize V_{DD} at the supply voltage used (2.7 to 5.5 V).

2. BLOCK DIAGRAM



- **Notes 1.** V_{DD} functions alternately as the A/D converter reference voltage input. When using the A/D converter, stabilize V_{DD} at the supply voltage used (2.7 to 5.5 V).
 - 2. Vss functions alternately as the ground potential of the A/D converter. Be sure to connect Vss to a stabilized GND (= 0 V).



3. PIN FUNCTIONS

3.1 Port Pins

Pin Name	I/O	Function		After Reset	Alternate-Function Pin
P20	I/O	Port 2.		Input	ANI0/TI000/TOH1
P21		•	utput mode in 1-bit units.		ANI1/TI010/ TO00/INTP0
P22 ^{Note}		software.	tor can be connected by setting		X2/ANI2 ^{Note}
P23 ^{Note}					X1/ANI3 ^{Note}
P32	I/O	Port 3	Can be set to input or output mode in 1-bit units. An on-chip pull-up resistor can be connected by setting software.	Input	INTP1
P34 ^{Note}	Input		Input only	Input	RESET ^{Note}
P40 to P47	I/O	Port 4. 8-bit I/O port. Can be set to input or o An on-chip pull-up resis software.	Input	-	

Note For the setting method for pin functions, see **5. OPTION BYTE**.

Caution The P22/X2/ANI2 and P23/X1/ANI3 pins are pulled down during reset.



3.2 Non-Port Pins

Pin Name	I/O	Function	After Reset	Alternate- Function Pin
INTP0	Input	External interrupt input for which the valid edge (rising edge, falling edge, or both rising and falling edges) can be specified	Input	P21/ANI1/TI010/ TO00
INTP1				P32
TI000	Input	External count clock input to 16-bit timer/event counter 00. Capture trigger input to capture registers (CR000 and CR010) of 16-bit timer/event counter 00	Input	P20/ANI0/TOH1
TI010		Capture trigger input to capture register (CR000) of 16-bit timer/event counter 00		P21/ANI1/TO00/ INTP0
TO00	Output	16-bit timer/event counter 00 output	Input	P21/ANI1/TI010/ INTP0
TOH1	Output	8-bit timer H1 output	Input	P20/ANI0/TI000
ANI0	Input	Analog input of A/D converter	Input	P20/TI000/TOH1
ANI1				P21/TI010/TO00/ INTP0
ANI2 ^{Note}				P22/X2 ^{Note}
ANI3 ^{Note}				P23/X1 ^{Note}
RESET Note	Input	System reset input	Input	P34 ^{Note}
X1 ^{Note}	Input	Connection of crystal/ceramic oscillator for system clock oscillation. External clock input.	-	P23/ANI3 ^{Note}
X2 ^{Note}	_	Connection of crystal/ceramic oscillator for system clock oscillation.		P22/ANI2 ^{Note}
V _{DD}	_	Positive power supply	_	-
Vss	_	Ground potential	_	-

Note For the setting method for pin functions, see **5. OPTION BYTE**.

Caution The P22/X2/ANI2 and P23/X1/ANI3 pins are pulled down during reset.

3.3 Pin I/O Circuits and Recommended Connection of Unused Pins

The input/output circuit type of each pin and recommended connection of unused pins is shown in Table 3-1. For the input/output circuit configuration of each type, refer to Figure 3-1.

Table 3-1. Type of I/O Circuit for Each Pin and Connection of Unused Pins

Pin Name	I/O Circuit Type	I/O	Recommended Connection of Unused Pin
P20/ANI0/TI000/TOH1	11	I/O	Input: Individually connect to VDD or Vss via resistor.
P21/ANI1/TI010/TO00/			Output: Leave open.
INTP0			
P22/ANI2/X2	36		Input: Individually connect to Vss via resistor.
P23/ANI3/X1			Output: Leave open.
P32/INTP1	8-A		Input: Individually connect to VDD or Vss via resistor.
			Output: Leave open.
P34/RESET	2	Input	Connect to VDD via resistor.
P40 to P47	8-A	I/O	Input: Individually connect to VDD or Vss via resistor.
			Output: Leave open.

Type 36 Type 2 feedback cut-off Schmitt-triggered input with hysteresis characteristics OSC enable Х1, X2, IN/OUT IN/OUT Type 8-A V_{DD} pullup enable VDD Pull up enable data ╾ P-ch output disable Data Comparator P-ch O IN/OUT N-ch Output Comparison disable voltage 7// pullup P-ch enable Type 11 data – ►P-ch Pull up output enable disable V_{DD} Data Comparator -○ IN/OUT Output -N-ch Comparison disable voltage Comparator P-ch ‡ _{Vss} Comparison

Figure 3-1. Pin Input/Output Circuits

voltage

Input enable

4. MEMORY SPACE

4.1 Memory Space

Products in the μ PD78F9210FH, 78F9211FH, and 78F9212FH can access up to 64 Kbytes of memory space. Figures 4-1 to 4-3 show the memory maps.

FFFFH Special function registers (SFR) 256×8 bits FF00H FEFFH Internal high-speed RAM 128 × 8 bits FE80H FE7FH Use prohibited Data memory space 03FFH 0400H 03FFH Program area 0082H 0081H Protect byte area 0080H Option byte area Program memory Flash memory 007FH space 1,024 × 8 bits CALLT table area 0040H 003FH Program area 0014H 0013H Vector table area 0000H 0000H

Figure 4-1. Memory Map (µPD78F9210FH)

Remark The option byte and protect byte are 1 byte each.

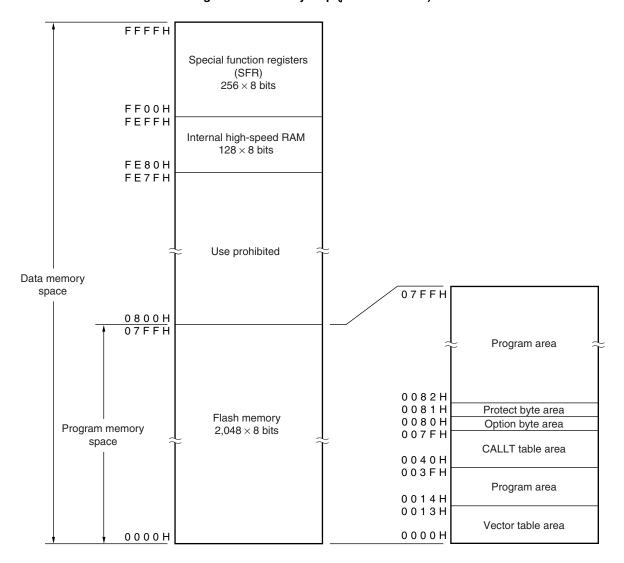


Figure 4-2. Memory Map (µPD78F9211FH)

Remark The option byte and protect byte are 1 byte each.

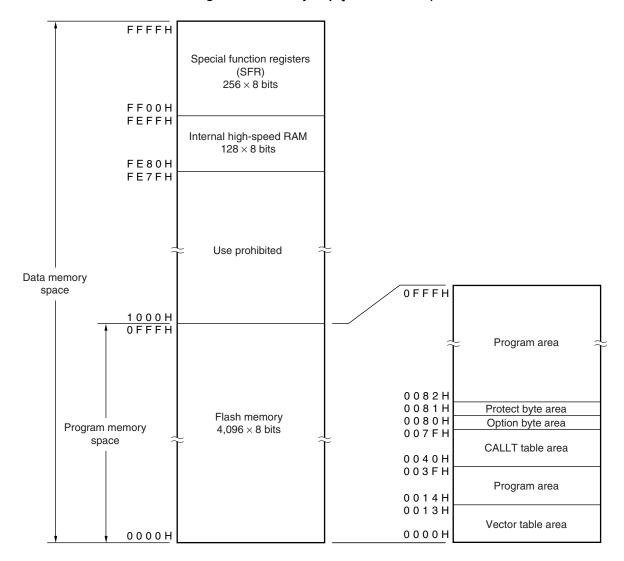


Figure 4-3. Memory Map (µPD78F9212FH)

Remark The option byte and protect byte are 1 byte each.

4.2 Memory Configuration

The 1/2/4 KB internal flash memory area is divided into 4/8/16 blocks and can be programmed/erased in block units. All the blocks can also be erased at once, by using a dedicated flash programmer.

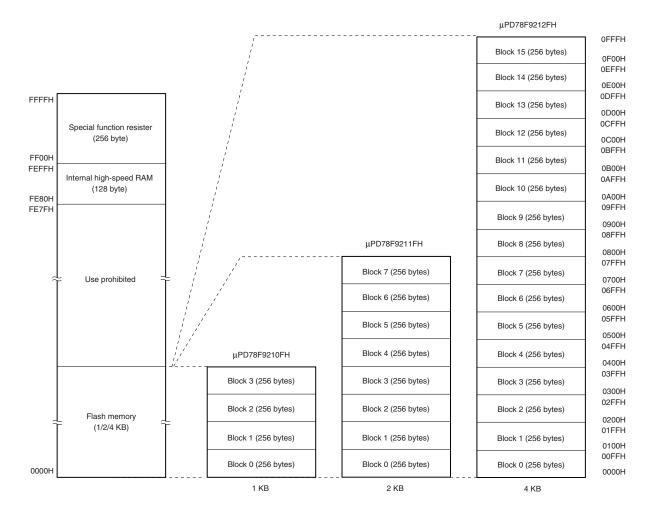


Figure 4-4. Flash Memory Mapping

5. OPTION BYTE

5.1 Functions of Option Byte

The address 0080H of the flash memory of the μ PD78F9210FH, 78F9211FH, and 78F9212FH is an option byte area. When power is supplied or when starting after a reset, the option byte is automatically referenced, and settings for the specified functions are performed. When using the product, be sure to set the following functions by using the option byte.

(1) Selection of system clock source

- High-speed internal oscillation clock
- Crystal/ceramic oscillation clock
- External clock input

(2) Low-speed internal oscillation clock oscillation

- Cannot be stopped.
- Can be stopped by software.

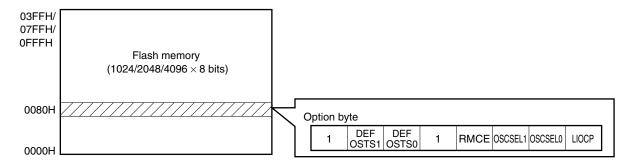
(3) Control of RESET pin

- Used as RESET pin
- RESET pin is used as an input port pin (P34).

(4) Oscillation stabilization time on power application or after reset release

- 210/fx
- 212/fx
- 2¹⁵/fx
- 217/fx

Figure 5-1. Positioning of Option Byte



5.2 Format of Option Byte

Format of option bytes is shown below.

Figure 5-2. Format of Option Byte (1/2)

Address: 0080H

7	6	5	4	3	2	1	0
1	DEFOSTS1	DEFOSTS0	1	RMCE	OSCSEL1	OSCSEL0	LIOCP

DEFOSTS1	DEFOSTS0	Oscillation stabilization time on power application or after reset release
0	0	2 ¹⁰ /fx (102.4 μs)
0	1	2 ¹² /fx (409.6 μs)
1	0	2 ¹⁵ /fx (3.27 ms)
1	1	2 ¹⁷ /fx (13.1 ms)

Caution The setting of this option is valid only when the crystal/ceramic oscillation clock is selected as the system clock source. No wait time elapses if the high-speed internal oscillation clock or external clock input is selected as the system clock source.

RMCE	Control of RESET pin		
1	Used as RESET pin.		
0	RESET pin is used as input port pin (P34).		

Caution Because the option byte is referenced after reset release, if a low level is input to the RESET pin before the option byte is referenced, then the reset state is not released.

Also, when setting 0 to RMCE, connect the pull-up resistor.

OSCSEL1	OSCSEL0	Selection of system clock source		
0	0	Crystal/ceramic oscillation clock		
0	1	External clock input		
1	×	High-speed internal oscillation clock		

Caution Because the X1 and X2 pins are also used as the P23/ANI3 and P22/ANI2 pins, the conditions under which the X1 and X2 pins can be used differ depending on the selected system clock source.

- (1) Crystal/ceramic oscillation clock is selected

 The X1 and X2 pins cannot be used as I/O port pins or analog input pins of A/D converter
 because they are used as clock input pins.
- (2) External clock input is selected

 Because the X1 pin is used as an external clock input pin, P23/ANI3 cannot be used as an I/O port pin or an analog input pin of A/D converter.
- (3) High-speed internal oscillation clock is selected P23/ANI3 and P22/ANI2 pins can be used as I/O port pins or analog input pins of A/D converter.

Remark ×: don't care

Figure 5-2. Format of Option Byte (2/2)

LIOCP	Low-speed internal oscillates
1	Cannot be stopped (oscillation does not stop even if 1 is written to the LSRSTOP bit)
0	Can be stopped by software (oscillation stops when 1 is written to the LSRSTOP bit)

- Cautions 1. If it is selected that low-speed internal oscillator cannot be stopped, the count clock to the watchdog timer (WDT) is fixed to low-speed internal oscillation clock.
 - 2. If it is selected that low-speed internal oscillator can be stopped by software, supply of the count clock to WDT is stopped in the HALT/STOP mode, regardless of the setting of bit 0 (LSRSTOP) of the low-speed internal oscillation mode register (LSRCM). Similarly, clock supply is also stopped when a clock other than the low-speed internal oscillation clock is selected as a count clock to WDT.

While the low-speed internal oscillator is operating (LSRSTOP = 0), the clock can be supplied to the 8-bit timer H1 even in the STOP mode.

Remarks 1. (): fx = 10 MHz

- **2.** For the oscillation stabilization time of the resonator, refer to the characteristics of the resonator to be used.
- **3.** An example of software coding for setting the option bytes is shown below.

OPB CSEG AT 0080H

DB 10010001B ; Set to option byte

; Low-speed internal oscillator cannot be stopped ; The system clock is a crystal or ceramic resonator. ; The RESET pin is used as an input-only port pin (P34).

; Minimum oscillation stabilization time (210/fx)

4. For details on the timing at which the option byte is referenced, see the chapter of the reset function 78K0S/KY1+ User's Manual (U16994E)

6. SOURCE CLOCK OF EACH TIMER

(1) Count clock selection by 16-bit timer/event counter 00 (TM00)

fxp (10 MHz)

fxp/22 (2.5 MHz)

fxp/28 (39.06 kHz)

TI000 pin valid edge^{Note}

Note The external clock requires a pulse longer than two cycles of the internal count clock (fxp).

Remarks 1. fxp: Oscillation frequency of clock supplied to peripheral hardware

2. (): fxp = 10 MHz

(2) Count clock selection by 8-bit timer/event counter H1 (TMH1)

fxp(10 MHz)

fxp/22(2.5 MHz)

fxp/24(625 kHz)

fxp/26(156.25 kHz)

fxp/212(2.44 kHz)

f_{RL}/27(1.88 kHz (TYP.))

Remarks 1. fxp: Oscillation frequency of clock to peripheral hardware

2. fr.L: Low-speed internal oscillation clock oscillation frequency

3. Figures in parentheses apply to operation at $f_{XP} = 10 \text{ MHz}$, $f_{RL} = 240 \text{ kHz}$ (TYP.).

(3) Overflow time setting by watchdog timer

Overflow time setting						
During Low-Speed Internal oscillation Clock Operation	During System Clock Operation					
2 ¹¹ /f _{RL} (4.27 ms)	2 ¹³ /fx (819.2 μs)					
2 ¹² /f _{RL} (8.53 ms)	2 ¹⁴ /fx (1.64 ms)					
2 ¹³ /f _{RL} (17.07 ms)	2 ¹⁵ /fx (3.28 ms)					
2 ¹⁴ /f _{RL} (34.13 ms)	2 ¹⁶ /fx (6.55 ms)					
2 ¹⁵ /f _{RL} (68.27 ms)	2 ¹⁷ /fx (13.11 ms)					
2 ¹⁶ /f _{RL} (136.53 ms)	2 ¹⁸ /fx (26.21 ms)					
2 ¹⁷ /f _{RL} (273.07 ms)	2 ¹⁹ /fx (52.43 ms)					
2 ¹⁸ /f _{RL} (546.13 ms)	2 ²⁰ /fx (104.86 ms)					

Remarks 1. fr.: Low-speed internal oscillation clock oscillation frequency

2. fx: System clock oscillation frequency

3. Figures in parentheses apply to operation at $f_{RL} = 480 \text{ kHz}$ (MAX.), $f_{X} = 10 \text{ MHz}$.



7. ELECTRICAL SPECIFICATIONS (TARGET VALUES)

Caution These specifications show target values, which may change after device evaluation. The operating voltage range may also change.

Absolute Maximum Ratings (TA = 25°C)

Parameter	Symbol	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.3 to +6.5	٧
	Vss		-0.3 to +0.3	V
Input voltage	Vı	P20 to P23, P32, P34, P40 to P47	-0.3 to V _{DD} + 0.3 ^{Note}	V
Output voltage	Vo		-0.3 to $V_{DD} + 0.3^{Note}$	V
Analog input voltage	Van		-0.3 to $V_{DD} + 0.3^{Note}$	V
Output current, high	Іон	Per pin	-10.0	mA
		Total of P20 to P23, P32, P40 to P47	-44.0	mA
Output current, low	loL	Per pin	20.0	mA
		Total of P20 to P23, P32, P40 to P47	44.0	mA
Operating ambient	TA	In normal operation mode	-40 to +85	°C
temperature		During flash memory programming		°C
Storage temperature	T _{stg}	Flash memory blank status	-65 to +150	°C
		Flash memory programming already performed	-40 to +125	°C

Note Must be 6.5 V or lower

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of port pins.



X1 Oscillator Characteristics (TA = -40 to +85°C, VDD = 2.0 to 5.5 V^{Note 1}, Vss = 0 V)

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Ceramic resonator	Vss X1 X2	Oscillation frequency (fx) ^{Note 2}		1		10.0	MHz
Crystal resonator	Vss X1 X2 C1 C2 C2 7777	Oscillation frequency (fx) ^{Note 2}		1		10.0	MHz
External	X1	X1 input	2.7 V ≤ V _{DD} ≤ 5.5 V	1		10.0	MHz
clock		frequency (fx) ^{Note 2}	$2.0 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	1		5.0	
		X1 input high-	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	0.045		0.5	μs
	\vdash	/low-level width (txH, txL)	2.0 V ≤ V _{DD} < 2.7 V	0.09		0.5	

- **Notes 1.** Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on clear (POC) circuit is 2.1 V \pm 0.1 V.
 - 2. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.

Caution When using the X1 oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.

- · Keep the wiring length as short as possible.
- Do not cross the wiring with the other signal lines.
- . Do not route the wiring near a signal line through which a high fluctuating current flows.
- Always make the ground point of the oscillator capacitor the same potential as Vss.
- Do not ground the capacitor to a ground pattern through which a high current flows.
- · Do not fetch signals from the oscillator.

Remark For the resonator selection and oscillator constant, users are required to either evaluate the oscillation themselves or apply to the resonator manufacturer for evaluation.

High-Speed Internal Oscillator Characteristics (TA = -40 to +85°C, VDD = 2.0 to 5.5 VNote 1, VSS = 0 V)

Resonator	Parameter	Conditions		MIN.	TYP.	MAX.	Unit
High-speed internal	Oscillation frequency (fx = 8	$2.7~V \leq V_{DD} \leq 5.5~V$	$T_A = -10 \text{ to } +70^{\circ}\text{C}$			±3	%
oscillator	MHz ^{Note 2}) deviation		T _A = -40 to +85°C			±5	%
	Oscillation frequency (fx) ^{Note 2}	2.0 V ≤ V _{DD} < 2.7 V		5.5			MHz

- **Notes 1.** Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on-clear (POC) circuit is 2.1 V \pm 0.1 V.
 - 2. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.

Low-Speed Internal Oscillator Characteristics (TA = -40 to +85°C, VDD = 2.0 to 5.5 VNote, VSS = 0 V)

Resonator	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Low-speed internal oscillator	Oscillation frequency (fr.)		120	240	480	kHz

Note Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on clear (POC) circuit is 2.1 V \pm 0.1 V.



DC Characteristics (TA = -40 to +85°C, VDD = 2.0 to 5.5 V Note, VSS = 0 V) (1/2)

Parameter	Symbol		Conditi	ons	MIN.	TYP.	MAX.	Unit
Output current, high	Іон	Per pin		$2.0~V \leq V_{DD} \leq 5.5~V$			- 5	mA
		Total of all pins		$4.0~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$			-25	mA
				2.0 V ≤ V _{DD} < 4.0 V			-15	mA
Output current, low	loL	Per pin		$2.0~V \leq V_{DD} \leq 5.5~V$			10	mA
		Total of all pins		$4.0~V \leq V_{DD} \leq 5.5~V$			30	mA
				2.0 V ≤ V _{DD} < 4.0 V			15	mA
Input voltage, high	V _{IH1}	P23 in external clo	ock mod	e and pins other than	0.8V _{DD}		V _{DD}	V
	V _{IH2}	P23 in other than	external	clock mode, P20 and	0.7V _{DD}		V _{DD}	V
Input voltage, low	VIL1	P23 in external clo	P23 in external clock mode and pins other than P20 and P21				0.2V _{DD}	V
	VIL2	P23 in other than external clock mode, P20 and P21			0		0.3V _{DD}	V
Output voltage, high	Vон	Total of output pin Іон = –15 mA	s	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ Iон = -5 mA	V _{DD} – 1.0			V
		Іон = –100 μА		2.0 V ≤ V _{DD} < 4.0 V	V _{DD} - 0.5			V
Output voltage, low	Vol	Total of output pin	s	$4.0~V \leq V_{DD} \leq 5.5~V$			1.3	V
		IoL = 30 mA		IoL = 10 mA				
		2.0 V ≤ V _{DD} < 4.0 V	V				0.4	٧
		IoL = 400 μA						
Input leakage current, high	Ішн	$V_I = V_{DD}$	Pins of	ther than X1			3	μΑ
Input leakage current, low	lul	V1 = 0 V	Pins of	ther than X1			-3	μΑ
Output leakage current, high	Ісон	Vo = VDD	Pins other than X2				3	μΑ
Output leakage current, low	ILOL	Vo = 0 V	Vo = 0 V Pins other than X2				-3	μΑ
Pull-up resistance value	Rpu	V1 = 0 V			10	30	100	kΩ
Pull-down resistance value	RPD	P22, P23, reset st	atus		10	30	100	kΩ

Note Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on clear (POC) circuit is 2.1 V \pm 0.1 V.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of port pins.

DC Characteristics (TA = -40 to +85°C, VDD = 2.0 to 5.5 V^{Note 1}, VSS = 0 V) (2/2)

Parameter	Symbol		Condition	S	MIN.	TYP.	MAX.	Unit
Supply	IDD1 Note 3	Crystal/ceramic	fx = 10 MHz	When A/D converter is stopped		6.1	12.2	mA
current ^{Note 2}		oscillation,	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When A/D converter is operating		7.6	15.2	
		external clock input oscillation	fx = 6 MHz	When A/D converter is stopped		5.5	11.0	mA
		operating	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When A/D converter is operating			14.0	
		mode ^{Note 6}	fx = 5 MHz	When A/D converter is stopped		3.0	6.0	mA
			$V_{DD} = 3.0 \text{ V} \pm 10\%^{\text{Note 5}}$	When A/D converter is operating		4.5	9.0	
	I _{DD2}	Crystal/ceramic	fx = 10 MHz	When peripheral functions are stopped		1.7	3.8	mA
		oscillation,	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When peripheral functions are operating			6.7	
		external clock input HALT	fx = 6 MHz	When peripheral functions are stopped		1.3	3.0	mA
		mode ^{Note 6}	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When peripheral functions are operating			6.0	
			fx = 5 MHz	When peripheral functions are stopped		0.48	1	mA
		$V_{DD} = 3.0 \text{ V} \pm 10\%^{\text{Note 5}}$	When peripheral functions are operating			2.1		
	IDD3 ^{Note 3} High-speed	fx = 8 MHz	When A/D converter is stopped		5.0	10.0	mA	
		internal oscillation operating mode ^{Note 7}	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When A/D converter is operating		6.5	13.0	
	I _{DD4}	High-speed	fx = 8 MHz	When peripheral functions are stopped		1.4	3.2	mA
		internal oscillation HALT mode ^{Note 7}	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 4}}$	When peripheral functions are operating			5.9	
	I _{DD5}	STOP mode	$V_{DD} = 5.0 \text{ V} \pm 10\%$	When low-speed internal oscillation is stopped		3.5	35.5	μΑ
			When low-speed internal oscillation is operating		17.5	63.5		
			V _{DD} = 3.0 V ±10%	When low-speed internal oscillation is stopped		3.5	15.5	μΑ
				When low-speed internal oscillation is operating		11.0	30.5	

- **Notes 1.** Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on clear (POC) circuit is $2.1 \text{ V} \pm 0.1 \text{ V}$.
 - 2. Total current flowing through the internal power supply (VDD). However, the current that flows through the pull-up resistors of ports is not included.
 - 3. IDD1 and IDD3 includ peripheral operation current.
 - 4. When the processor clock control register (PCC) is set to 00H.
 - 5. When the processor clock control register (PCC) is set to 02H.
 - **6.** When crystal/ceramic oscillation clock, external clock input is selected as the system clock source using the option byte.
 - 7. When high-speed internal oscillation clock is selected as the system clock source using the option byte.



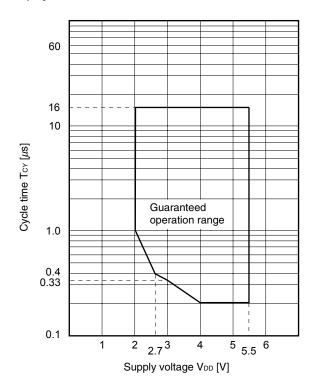
AC Characteristics

Basic operation (T_A = -40 to +85°C, V_{DD} = 2.0 to 5.5 V^{Note 1}, V_{SS} = 0 V)

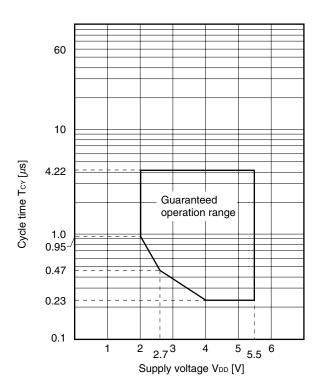
Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Cycle time (minimum	Tcy	Crystal/ceramic oscillation	$4.0~V \leq V_{DD} \leq 5.5~V$	0.2		16	μs
instruction execution time)		clock, external clock input	$3.0~\textrm{V} \leq \textrm{V}_\textrm{DD} < 4.0~\textrm{V}$	0.33		16	μs
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.0~\textrm{V}$	0.4		16	μs
			$2.0~\textrm{V} \leq \textrm{V}_\textrm{DD} < 2.7~\textrm{V}$	1		16	μs
		High-speed internal oscillation clock	$4.0~V \leq V_{DD} \leq 5.5~V$	0.23		4.22	μs
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 4.0~\textrm{V}$	0.47		4.22	μs
			$2.0~\textrm{V} \leq \textrm{V}_\textrm{DD} < 2.7~\textrm{V}$	0.95		4.22	μs
TI000/TI010 input high-level width, low-level width	tтін, tті∟	$4.0~V \le V_{DD} \le 5.5~V$		2/fsam+ 0.1 ^{Note 2}			μs
		2.0 V ≤ V _{DD} < 4.0 V		2/fsam+ 0.2 ^{Note 2}			μs
Interrupt input high-level	tinth,			1			μs
width, low-level width	tintl						
RESET input low-level width	trsl			2			μs

- **Notes 1.** Use this product in a voltage range of 2.2 to 5.5 V because the detection voltage (V_{POC}) of the power-on clear (POC) circuit is 2.1 V \pm 0.1 V.
 - 2. Selection of fsam = fxp, fxp/4, or fxp/256 is possible using bits 0 and 1 (PRM000, PRM001) of prescaler mode register 00 (PRM00). Note that when selecting the Tl000/Tl010 valid edge as the count clock, fsam = fxp.

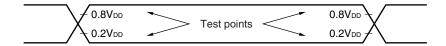
TCY vs. VDD (Crystal/Ceramic Oscillation Clock, External Clock Input)



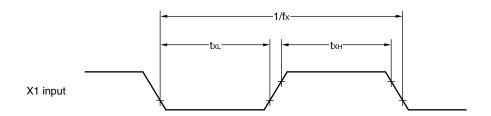
Tcy vs. VDD (High-speed internal oscillator Clock)



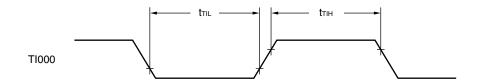
AC Timing Test Points (Excluding X1 Input)



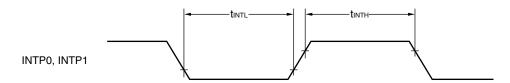
Clock Timing



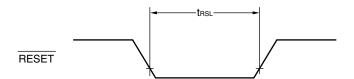
TI000 Timing



Interrupt Input Timing



RESET Input Timing



A/D Converter Characteristics (T_A = -40 to +85°C, 2.7 V ≤ V_{DD} ≤ 5.5 V^{Note 1}, V_{SS} = 0 V^{Note 2})

(1) A/D converter basic characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution			10	10	10	bit
Conversion time	tconv	$4.5~V \leq V_{DD} \leq 5.5~V$	3.0		100	μs
		$4.0 \text{ V} \le \text{V}_{DD} < 4.5 \text{ V}$	4.8		100	μs
		$2.85 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}$	6.0		100	μs
		$2.7 \text{ V} \le \text{V}_{DD} < 2.85 \text{ V}$	14.0		100	μs
Analog input voltage	VAIN		Vss ^{Note 2}		V _{DD}	V

(2) A/D Converter Characteristics (high-speed internal oscillation clock)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Overall error ^{Notes 3, 4}	AINL			-0.1 to +0.2 ^{Note 5}	-0.35 to +0.45	%FSR
Zero-scale error ^{Notes 3, 4}	Ezs			-0.1 to +0.2 ^{Note 5}	-0.35 to +0.45	%FSR
Full-scale error ^{Notes 3, 4}	Efs			-0.1 to +0.2 ^{Note 5}	-0.35 to +0.40	%FSR
Integral non-linearity error ^{Note 3}	ILE			±1 Note 5	±3	LSB
Differential non-linearity error ^{Note 3}	DLE			±1 Note 5	±1.5	LSB

(3) A/D Converter Characteristics (Crystal/Ceramic Oscillation Clock, External Clock)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Overall error ^{Notes 1, 2}	AINL	$4.0~V \leq V_{DD} \leq 5.5~V$		-0.20 to +0.35 ^{Note 5}	-0.35 to +0.65	%FSR
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}$		±0.25 ^{Note 5}	-0.35 to +0.55	%FSR
Zero-scale error ^{Notes 3, 4}	Ezs	$4.0~V \leq V_{DD} \leq 5.5~V$		-0.20 to +0.35 ^{Note 5}	-0.35 to +0.65	%FSR
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}$		±0.25 ^{Note 5}	-0.35 to +0.55	%FSR
Full-scale error ^{Notes 3, 4}	Efs	$4.0~V \leq V_{DD} \leq 5.5~V$		-0.20 to +0.35 ^{Note 5}	-0.35 to +0.55	%FSR
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}$		±0.25 ^{Note 5}	-0.35 to +0.50	%FSR
Integral non-linearity error ^{Note 3}	ILE	$4.0~V \leq V_{DD} \leq 5.5~V$		±1.5 ^{Note 5}	±3.0	LSB
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}$		±1.5 ^{Note 5}	±4.0	LSB
Differential non-linearity error ^{Note 3}	DLE	$4.0~V \leq V_{DD} \leq 5.5~V$		±1.0 ^{Note 5}	±2.5	LSB
		$2.7 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}$		±1.0 ^{Note 5}	±2.5	LSB

- **Notes 1.** In the μ PD78F9210FH, 78F9211FH, 78F9212FH, V_{DD} functions alternately as the A/D converter reference voltage input. When using the A/D converter, stabilize V_{DD} at the supply voltage used (2.7 to 5.5 V).
 - 2. In the μ PD78F9210FH, 78F9211FH, 78F9212FH, Vss functions alternately as the ground potential of the A/D converter. Be sure to connect Vss to a stabilized GND (= 0 V).
 - 3. Excludes quantization error ($\pm 1/2$ LSB).
 - 4. This value is indicated as a ratio (%FSR) to the full-scale value.
 - 5. A value when HALT mode is set by an instruction immediately after A/D conversion starts.

Caution The conversion accuracy may be degraded if the level of a port that is not used for A/D conversion is changed during A/D conversion.

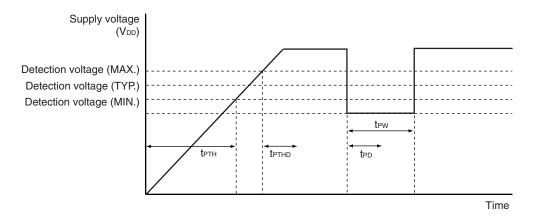


POC Circuit Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOC		2.0	2.1	2.2	٧
Power supply rise time	tртн	VDD: $0 \text{ V} \rightarrow 2.1 \text{ V}$	1.5			μs
Response delay time 1 ^{Note 1}	tртно	When power supply rises, after reaching detection voltage (MAX.)			3.0	ms
Response delay time 2 ^{Note 2}	t PD	When power supply falls			1.0	ms
Minimum pulse width	tpw		0.2			ms

- Notes 1. Time required from voltage detection to internal reset release.
 - **2.** Time required from voltage detection to internal reset signal generation.

POC Circuit Timing





LVI Circuit Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVIO		4.1	4.3	4.5	V
	V _{LVI1}		3.9	4.1	4.3	٧
	V _{LVI2}		3.7	3.9	4.1	V
	V _{LVI3}		3.5	3.7	3.9	V
	V _{LVI4}		3.3	3.5	3.7	٧
	V _{LVI5}		3.15	3.3	3.45	V
	V _{LVI6}		2.95	3.1	3.25	V
	V _{LVI7}		2.7	2.85	3.0	V
	V _{LVI8}		2.5	2.6	2.7	٧
	V _{LVI9}		2.25	2.35	2.45	٧
Response time ^{Note 1}	tld			0.2	2.0	ms
Minimum pulse width	tLW		0.2			ms
Operation stabilization wait time ^{Note 2}	tlwait			0.1	0.2	ms

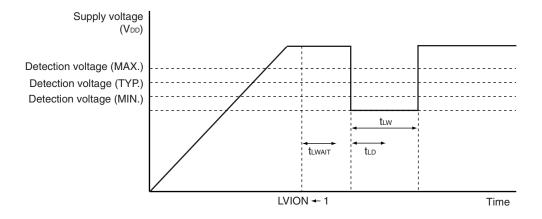
Notes 1. Time required from voltage detection to interrupt output or internal reset signal generation.

2. Time required from setting LVION to 1 to operation stabilization.

 $\textbf{Remarks 1.} \ \ V_{\text{LVI0}} > V_{\text{LVI1}} > V_{\text{LVI2}} > V_{\text{LVI4}} > V_{\text{LVI5}} > V_{\text{LVI6}} > V_{\text{LVI7}} > V_{\text{LVI8}} > V_{\text{LVI9}}$

2. $V_{POC} < V_{LVIm} (m = 0 \text{ to } 9)$

LVI Circuit Timing



Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V _{DDDR}		2.0		5.5	V
Release signal set time	tsrel		0			μs



Flash Memory Programming Characteristics (T_A = −40 to +85°C, 2.7 V ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Supply current	IDD	V _{DD} = 5.5 V				7.0	mA
Erasure count ^{Note} (per 1 block)	Nerase	T _A = -40 to +85°C		1000			Times
Chip erase time	TCERASE	$T_A = -10 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{DD} \leq 5.5~V$			0.8	s
		Nerase ≤ 100	$3.5~V \leq V_{\text{DD}} < 4.5~V$			1.0	s
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			1.2	s
		$T_A = -10 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			4.8	s
		Nerase ≤ 1000	$3.5~V \leq V_{\text{DD}} < 4.5~V$			5.2	s
			$2.7~V \leq V_{\text{DD}} < 3.5~V$			6.1	s
		$T_A = -40 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			1.6	s
		Nerase ≤ 100	$3.5~\textrm{V} \leq \textrm{V}_\textrm{DD} < 4.5~\textrm{V}$			1.8	s
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			2.0	s
		$T_{\text{A}} = -40 \text{ to } +85^{\circ}\text{C},$ $N_{\text{ERASE}} \leq 1000$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			9.1	s
			$3.5~\textrm{V} \leq \textrm{V}_\textrm{DD} < 4.5~\textrm{V}$			10.1	s
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			12.3	s
Block erase time Tee	TBERASE	$T_A = -10 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			0.4	s
		Nerase ≤ 100	$3.5~V \leq V_{DD} < 4.5~V$			0.5	s
		$T_A = -10 \text{ to } +85^{\circ}\text{C},$	$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			0.6	s
			$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			2.6	s
			Nerase ≤ 1000	$3.5~\textrm{V} \leq \textrm{V}_\textrm{DD} < 4.5~\textrm{V}$			2.8
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			3.3	s
		$T_A = -40 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			0.9	s
		Nerase ≤ 100	$3.5~V \leq V_{\text{DD}} < 4.5~V$			1.0	s
			$2.7~\textrm{V} \leq \textrm{V}_\textrm{DD} < 3.5~\textrm{V}$			1.1	s
		$T_A = -40 \text{ to } +85^{\circ}\text{C},$	$4.5~V \leq V_{\text{DD}} \leq 5.5~V$			4.9	s
		Nerase ≤ 1000	$3.5~V \leq V_{\text{DD}} < 4.5~V$			5.4	s
			$2.7~V \leq V_{\text{DD}} < 3.5~V$			6.6	s
Byte write time	TWRITE	Ta = -40 to +85°C, Nerase ≤ 1000				150	μs
Internal verify	TVERIFY	Per 1 block				6.8	ms
		Per 1 byte	·			27	μs
Blank check	Твыкснк	Per 1 block				480	μs
Retention years		$T_A = 85^{\circ}C^{\text{Note 2}}$, $N_{\text{ERASE}} \le 1000$		10			Years

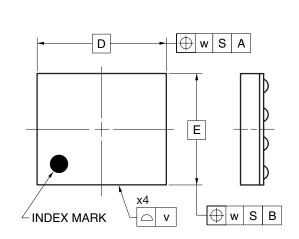
Notes 1. Depending on the erasure count (Nerase), the erase time varies. Refer to the chip erase time and block erase time parameters.

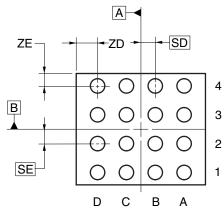
Remark When a product is first written after shipment, "erase → write" and "write only" are both taken as one rewrite.

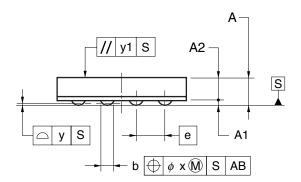
^{2.} When the average temperature when operating and not operating is 85°C.

8. PACKAGE DRAWING (PRELIMINARY)

16-PIN FBGA (WAFER LEVEL CSP) (1.93x2.24)







	(UNIT:mm)
ITEM	DIMENSIONS
D	2.24
Е	1.93
٧	0.15
W	0.20
Α	0.48±0.04
A1	0.08±0.02
A2	0.40
е	0.50
SD	0.25
SE	0.25
b	0.25±0.05
х	0.05
у	0.08
y1	0.20
ZD	0.37
ZE	0.215
	DICTU EO OAO

P16FH-50-2A2

© NEC Electronics Corporation 2005



APPENDIX A. RELATED DOCUMENTS

The related document indicated in this publication may include preliminary versions. However, preliminary versions are not marked as such.

Documents Related to Devices

Document Name	Document No.
μ PD78F9210FH, 78F9211FH, 78F9212FH Preliminary Product Information	This manual
78K0S/KY1+ User's Manual	U16994E
78K/0S Series Instructions User's Manual	U12326E

Documents Related to Development Tools (Software) (User's Manuals)

Document N	Document No.	
RA78K0S Ver. 1.50 Assembler Package	Operation	U17391E
	Language	U17390E
	Structured Assembly Language	U17389E
CC78K0S Ver. 1.60 C Compiler	Operation	U17416E
	Language	U17415E
SM+ System Simulator	Operation	U17246E
	External Part User Open Interface Specifications	U17247E
ID78K0S-QB Ver. 2.81 Integrated Debugger	Operation	U17287E
PM+ Ver. 5.20		U16934E

Documents Related to Development Tools (Hardware) (User's Manuals)

Document Name	Document No.
IE-78K0S-NS In-Circuit Emulator	U13549E
IE-78K0S-NS-A In-Circuit Emulator	U15207E
QB-78K0SKX1H In-Circuit Emulator	U17272E

Documents Related to Flash Memory Programming

Document Name	Document No.
PG-FP4 Flash Memory Programmer User's Manual	U15260E
PG-FPL2 Flash Memory Programmer User's Manual	U17307E

Caution The related documents listed above are subject to change without notice. Be sure to use the latest version of each document when designing.

Other Documents

Document Name	Document No.
SEMICONDUCTOR SELECTION GUIDE - Products and Packages -	X13769X
Semiconductor Device Mount Manual	Note
Quality Grades on NEC Semiconductor Devices	C11531E
NEC Semiconductor Device Reliability/Quality Control System	C10983E
Guide to Prevent Damage for Semiconductor Devices by Electrostatic Discharge (ESD)	C11892E

Note See the "Semiconductor Device Mount Manual" website (http://www.necel.com/pkg/en/mount/index.html).

Caution The related documents listed above are subject to change without notice. Be sure to use the latest version of each document when designing.

NOTES FOR CMOS DEVICES —

1 VOLTAGE APPLICATION WAVEFORM AT INPUT PIN

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between $V_{\rm IL}$ (MAX) and $V_{\rm IH}$ (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between $V_{\rm IL}$ (MAX) and $V_{\rm IH}$ (MIN).

(2) HANDLING OF UNUSED INPUT PINS

Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.

③ PRECAUTION AGAINST ESD

A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.

(4) STATUS BEFORE INITIALIZATION

Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.

(5) POWER ON/OFF SEQUENCE

In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current.

The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.

6 INPUT OF SIGNAL DURING POWER OFF STATE

Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

SuperFlash is a registered trademark of Silicon Storage Technology, Inc. in several countries including the United States and Japan.

Caution: This product uses SuperFlash® technology licensed from Silicon Storage Technology, Inc.

- The information contained in this document is being issued in advance of the production cycle for the product. The parameters for the product may change before final production or NEC Electronics Corporation, at its own discretion, may withdraw the product prior to its production.
- Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without the prior written consent
 of NEC Electronics. NEC Electronics assumes no responsibility for any errors that may appear in this document.
- NEC Electronics does not assume any liability for infringement of patents, copyrights or other intellectual property
 rights of third parties by or arising from the use of NEC Electronics products listed in this document or any other
 liability arising from the use of such products. No license, express, implied or otherwise, is granted under any
 patents, copyrights or other intellectual property rights of NEC Electronics or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative purposes
 in semiconductor product operation and application examples. The incorporation of these circuits, software and
 information in the design of a customer's equipment shall be done under the full responsibility of the customer. NEC
 Electronics assumes no responsibility for any losses incurred by customers or third parties arising from the use of
 these circuits, software and information.
- While NEC Electronics endeavors to enhance the quality, reliability and safety of NEC Electronics products, customers agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize risks of damage to property or injury (including death) to persons arising from defects in NEC Electronics products, customers must incorporate sufficient safety measures in their design, such as redundancy, fire-containment and anti-failure features.
- NEC Electronics products are classified into the following three quality grades: "Standard", "Special" and "Specific".
 The "Specific" quality grade applies only to NEC Electronics products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of an NEC Electronics products depend on its quality grade, as indicated below. Customers must check the quality grade of each NEC Electronics product before using it in a particular application.
 - "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots.
 - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).
 - "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC Electronics products is "Standard" unless otherwise expressly specified in NEC Electronics data sheets or data books, etc. If customers wish to use NEC Electronics products in applications not intended by NEC Electronics, they must contact an NEC Electronics sales representative in advance to determine NEC Electronics' willingness to support a given application.

(Note)

- (1) "NEC Electronics" as used in this statement means NEC Electronics Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC Electronics products" means any product developed or manufactured by or for NEC Electronics (as defined above).

M5D 02.11-1



For further information, please contact:

NEC Electronics Corporation

1753, Shimonumabe, Nakahara-ku, Kawasaki, Kanagawa 211-8668, Japan Tel: 044-435-5111 http://www.necel.com/

[America]

NEC Electronics America, Inc.

2880 Scott Blvd.
Santa Clara, CA 95050-2554, U.S.A.
Tel: 408-588-6000
800-366-9782
http://www.am.necel.com/

[Europe]

NEC Electronics (Europe) GmbH

Arcadiastrasse 10 40472 Düsseldorf, Germany Tel: 0211-65030 http://www.eu.necel.com/

Hanover Office

Podbielskistrasse 164 30177 Hannover Tel: 0 511 33 40 2-0

Munich Office

Werner-Eckert-Strasse 9 81829 München Tel: 0 89 92 10 03-0

Stuttgart Office

Industriestrasse 3 70565 Stuttgart Tel: 0 711 99 01 0-0

United Kingdom Branch

Cygnus House, Sunrise Parkway Linford Wood, Milton Keynes MK14 6NP, U.K. Tel: 01908-691-133

Succursale Française

9, rue Paul Dautier, B.P. 52180 78142 Velizy-Villacoublay Cédex France Tel: 01-3067-5800

Sucursal en España

Juan Esplandiu, 15 28007 Madrid, Spain Tel: 091-504-2787

Tyskland Filial

Täby Centrum Entrance S (7th floor) 18322 Täby, Sweden Tel: 08 638 72 00

Filiale Italiana

Via Fabio Filzi, 25/A 20124 Milano, Italy Tel: 02-667541

Branch The Netherlands

Limburglaan 5 5616 HR Eindhoven The Netherlands Tel: 040 265 40 10

[Asia & Oceania]

NEC Electronics (China) Co., Ltd

7th Floor, Quantum Plaza, No. 27 ZhiChunLu Haidian District, Beijing 100083, P.R.China TEL: 010-8235-1155 http://www.cn.necel.com/

NEC Electronics Shanghai Ltd.

Room 2509-2510, Bank of China Tower, 200 Yincheng Road Central, Pudong New Area, Shanghai P.R. China P.C:200120 Tel: 021-5888-5400 http://www.cn.necel.com/

NEC Electronics Hong Kong Ltd.

12/F., Cityplaza 4, 12 Taikoo Wan Road, Hong Kong Tel: 2886-9318 http://www.hk.necel.com/

Seoul Branch

11F., Samik Lavied'or Bldg., 720-2, Yeoksam-Dong, Kangnam-Ku, Seoul, 135-080, Korea Tel: 02-558-3737

NEC Electronics Taiwan Ltd.

7F, No. 363 Fu Shing North Road Taipei, Taiwan, R. O. C. Tel: 02-2719-2377

NEC Electronics Singapore Pte. Ltd.

238A Thomson Road, #12-08 Novena Square, Singapore 307684 Tel: 6253-8311 http://www.sg.necel.com/

G05.11-1A